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3772 U.S. PTO

**UTILITY PATENT APPLICATION TRANSMITTAL  
(Large Entity)***(Only for new nonprovisional applications under 37 CFR 1.53(b))*Docket No.  
BUR980145US2Total Pages in this Submission  
3**TO THE ASSISTANT COMMISSIONER FOR PATENTS**Box Patent Application  
Washington, D.C. 20231

Transmitted herewith for filing under 35 U.S.C. 111(a) and 37 C.F.R. 1.53(b) is a new utility patent application for an invention entitled:

**METHOD FOR TRANSLATING TWO-DIMENSIONAL CELL-COORDINATES OF A MEMORY PRODUCT TO  
N-DIMENSIONAL PHYSICAL ADDRESSES**

and invented by:

**Daniel Ben-Ezri**jc530 U.S. PTO  
09/48865  
01/21/00If a **CONTINUATION APPLICATION**, check appropriate box and supply the requisite information:☐ Continuation ☐ Divisional ☒ Continuation-in-part (CIP) of prior application No.: 09/182,168

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Enclosed are:

**Application Elements**

1. ☒ Filing fee as calculated and transmitted as described below
2. ☒ Specification having 46 pages and including the following:
  - a. ☒ Descriptive Title of the Invention
  - b. ☐ Cross References to Related Applications (if applicable)
  - c. ☐ Statement Regarding Federally-sponsored Research/Development (if applicable)
  - d. ☐ Reference to Microfiche Appendix (if applicable)
  - e. ☒ Background of the Invention
  - f. ☒ Brief Summary of the Invention
  - g. ☒ Brief Description of the Drawings (if drawings filed)
  - h. ☒ Detailed Description
  - i. ☒ Claim(s) as Classified Below
  - j. ☒ Abstract of the Disclosure

**UTILITY PATENT APPLICATION TRANSMITTAL**  
**(Large Entity)**

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Total Pages in this Submission  
**3**

**Application Elements (Continued)**

3. ☒ Drawing(s) *(when necessary as prescribed by 35 USC 113)*

- a. ☒ Formal                      Number of Sheets                      7 (Figs. 1-7)  
b. ☐ Informal                      Number of Sheets

4. ☒ Oath or Declaration

- a. ☒ Newly executed *(original or copy)*                      ☐ Unexecuted  
b. ☐ Copy from a prior application (37 CFR 1.63(d)) *(for continuation/divisional application only)*

- c. ☒ With Power of Attorney                      ☐ Without Power of Attorney

d. ☐ DELETION OF INVENTOR(S)

Signed statement attached deleting inventor(s) named in the prior application,  
see 37 C.F.R. 1.63(d)(2) and 1.33(b).

5. ☐ Incorporation By Reference *(usable if Box 4b is checked)*

The entire disclosure of the prior application, from which a copy of the oath or declaration is supplied under Box 4b, is considered as being part of the disclosure of the accompanying application and is hereby incorporated by reference therein.

6. ☐ Computer Program in Microfiche *(Appendix)*

7. ☐ Nucleotide and/or Amino Acid Sequence Submission *(if applicable, all must be included)*

- a. ☐ Paper Copy  
b. ☐ Computer Readable Copy *(identical to computer copy)*  
c. ☐ Statement Verifying Identical Paper and Computer Readable Copy

**Accompanying Application Parts**

8. ☐ Assignment Papers *(cover sheet & document(s))*

9. ☐ 37 CFR 3.73(B) Statement *(when there is an assignee)*

10. ☐ English Translation Document *(if applicable)*

11. ☒ Information Disclosure Statement/PTO-1449                      ☒ Copies of IDS Citations

12. ☐ Preliminary Amendment

13. ☒ Acknowledgment postcard

14. ☒ Certificate of Mailing

☐ First Class                      ☒ Express Mail *(Specify Label No.):* **EL046032438US**

**APPLICATION  
FOR  
UNITED STATES LETTERS PATENT**

**APPLICANT NAME: Daniel Ben-Ezri**

**TITLE: METHOD FOR TRANSLATING TWO-DIMENSIONAL  
CELL-COORDINATES OF A MEMORY PRODUCT TO  
N-DIMENSIONAL PHYSICAL ADDRESSES**

**DOCKET NO. BUR980145US2**

**INTERNATIONAL BUSINESS MACHINES CORPORATION**

**Express Certificate of Mailing EL046032438US**

**METHOD FOR TRANSLATING TWO-DIMENSIONAL CELL-  
COORDINATES OF A MEMORY PRODUCT TO N-DIMENSIONAL  
PHYSICAL ADDRESSES**

**BACKGROUND OF THE INVENTION**

5

*Field of the Invention*

The present invention generally relates to memory address translation and more particularly to an improved method for translating two-dimensional cell coordinates of a memory to n-dimensional physical addresses.

*Description of the Related Art*

10

In the random access memory (RAM) test world, one of the most important tools for viewing and characterizing the test results of the Device Under Test (DUT) is a system that identifies the defective bits shipped from the tester (a.k.a. "failmap") in a buffer and displays the failmap on a monitor in a two-dimensional layout. Such a system is referred to herein as Real-Time-Display (RTD).

15

A real-time-display system, however, is expected to provide more than just displaying the (failed and non-failed) bits. It has to provide some visual cues

about the location/identity of each and every bit that is investigated by the test person (hereafter referred to as "the user"), along with its *buffer coordinate* and *physical address*.

The buffer is regarded as a two-dimensional plane (although it is usually organized internally, in the test system, as a one-dimensional stream of bits) because the display, which is two-dimensional by nature, is considered to be a direct representation of the buffer contents. Therefore, a *buffer coordinate* is a set of two numbers (x, y), describing the bit's location in the buffer. Buffer coordinates give the user a general idea about the location of bits in the physical device under test (since the buffer layout attempts to be a one-to-one representation the DUT's physical layout), but what the user is really interested in is the *physical address* of a given bit.

A bit's physical address is most closely related to the bit's electrical address. That is, when accessing the bit from an external circuit, a row address and a column address are applied to the device under test's electrical pins and the bit's value is read from (or applied to, in the case of a memory write operation) one of a set of I/O pins. The row address, the column address and the I/O pin number define the bit's *electrical address*. The physical address is essentially the same thing as the electrical address, except that the physical address definition is more flexible. The bit's row is sometimes specified in terms of a row number or word-line. The bit's column - in terms of column number, column-select or bit-line. I/Os are also referred to as DQs. In addition, the user might be interested not

only in these three attributes, but also a bank number, a segment number, a unit number, etc.

Since each device under test bit can be uniquely described by either a buffer coordinate or a physical address, each physical address corresponds to one and only one buffer coordinate - and vice versa. The process of deriving a physical address from a buffer coordinate is called "buffer to physical address translation" (hereafter referred to as simply "address translation").

Every memory product has its own (usually unique) address translation scheme. Therefore, in order for a real-time-display system to provide physical addresses for a particular device under test, the real-time-display system has to know how to perform that device under test's address translation from the buffer coordinates (which are always known, by definition).

An immediate and straightforward approach to provide that information to the real-time-display system would be to use a lookup table (LUT) or an array of look up tables that describe address translation for the entire device under test. But this approach is impractical, since it requires and consumes huge amounts of memory in the real-time-display's system controller.

In an exemplary conventional solution to the address translation problem in real-time-display systems, the real-time-display programmer receives from the users (verbally or on paper or both) a description of the physical addresses layout of the device under test to be supported. The programmer then finds and/or creates a pattern, a function or an algorithm that can translate every buffer

coordinate to its corresponding physical address for that particular device under test. Conventionally, there were very few cases in which one such algorithm could describe two or more different memory products.

The programmer then implements the algorithm in a computer language, such as "C" (the language in which the real-time-display system's software is written), compiles it, integrates it into the real-time-display software and tests the "new" program. The programmer then installs/updates a copy of the new version on each real-time-display system that is going to be used for testing that particular device under test. The real-time-display systems, on which the updated version is installed, are now ready to report physical addresses. However, if an error (or a minor inaccuracy) in the address translation has been detected by the users, the process needs to be repeated.

The existing solution has the following drawbacks. First, the system's software needs to be upgraded for every new memory product. The users completely depend on the test system's programmer to support the new product. This makes turn around time substantially longer than if the users could simply apply their knowledge directly to the program. Every such "product support code" is rarely re-used for another product since there isn't a concept or a unified approach for describing the device under test, thus forcing the programmer to re-invent/re-think a description/algorithm for every new product. Thus, the programmer needs to learn and know at least the address translation aspect of each and every product to be supported on the real-time-display. Further, modifying

the system's software source code, compiling and linking it can introduce bugs to the entire real-time-display system - not only the address translation part.

Using the exemplary conventional solution described above, almost every real-time-display system is unique in the sense that it supports a different collection of memory products. This poses a configuration management problem for the installed base of a large number of systems. The present invention overcomes these disadvantages, as discussed below.

### SUMMARY OF THE INVENTION

It is, therefore, an object of the present invention to provide a structure and method for translating address buffer coordinates for a device under test having two or more similar repeatable units. The method comprises identifying a repeatable unit of the repeatable units, preparing a look up table for translating buffer coordinates of a reference unit of the repeatable units, displacing information from the look up table to correspond to the repeatable units and modifying the result by a linear operation and/or a scalar translation table comprising key-value pairs.

The displacing process can include mirroring the information from the look up table to correspond to the repeatable units. The reference unit may be a smallest repeatable unit and the method can also include the processes of identifying a first level of repeatable units, having a size larger than the smallest



repeatable unit, identifying a second level of repeatable units, having a size larger than the first level of repeatable units, and recursively displacing the information from the look up table to correspond respectively to the smallest repeatable units, the first level of repeatable units and second level of repeatable units.

5           The displacing process combined with the linear operation or a scalar translation table comprising key-value pairs comprises translating the buffer coordinates using one of the following functions  $g(x,y) = A \bullet f(ax + b, cy + d) + B$ ; and  $g(x,y) = \text{MAP}[f(ax + b, cy + d)]$ , and/or a combination of both, wherein variable A comprises one of an amplification and pattern reversal value, variable  
10       B comprises a linear displacement of said information from said look up table, variable b comprises a horizontal displacement from said reference unit, variable d comprises a vertical displacement from said reference unit, variable a comprises horizontal mirroring, variable c comprises vertical mirroring, and MAP is a scalar translation table comprising key-value pairs.

## 15                           **BRIEF DESCRIPTION OF THE DRAWINGS**

The foregoing and other objects, aspects and advantages will be better understood from the following detailed description of preferred embodiments of the invention with reference to the drawings, in which:

20       Figure 1 is a schematic diagram of a computer system according to the invention;

Figure 2 is a flow diagram illustrating a preferred method of the invention;

Figure 3 is a flow diagram further detailing the process described in block 20 in Figure 2;

Figure 4 is a flow diagram further detailing the process described in block 22 in Figure 2;

Figure 5 is a flow diagram illustrating another embodiment of the invention;

Figure 6 is a flow diagram further detailing the process described in block 50 in Figure 5; and

Figure 7 is a flow diagram further detailing the process described in block 52 in Figure 5.

## **DETAILED DESCRIPTION OF PREFERRED EMBODIMENTS OF THE INVENTION**

### **I. Initial Embodiments**

The inventive address translation method enables the real-time-display system to be identical everywhere, yet be capable of supporting any device under test by letting the user describe the device under test's address translation directly

to the system while the system is running, using a simple and concise Product Description Language (PDL) along with a mathematical model.

In real-time-display systems, there is a need to translate a two-dimensional coordinate (x,y) to an N-dimensional one (N = 1, 2, 3, 4,...):

$$(x,y) \rightarrow (x',y',z',w',v',...) \quad (1)$$

Where x', y' and z' correspond to bit-line, word-line and DQ, respectively. The other "dimensions" (e.g. w', v') can correspond to further partitioning such as segment number, unit number, "octant" and more.

The vector (x', y', z', w', v'...) will be referred to herein as the *translated coordinate*, and the number of elements it contains as its *dimension*.

Such translation can be produced by an array of functions, as follows:

$$\begin{aligned} x' &= f^x(x,y) \\ y' &= f^y(x,y) \\ z' &= f^z(x,y) \\ w' &= f^w(x,y) \\ v' &= f^v(x,y) \end{aligned} \quad (2)$$

which can also be described as a vector of functions (for shorter notation):

$$(x',y',z',w',v',...) = \vec{F}(x,y) \quad (3)$$

The foregoing should correctly translate the entire device under test area for any device under test.

For the sake of conciseness, any discussion herein of a memory product (or device under test) will refer only to its address-translation aspect. For example,  
5 "DUT description" as used herein is considered equivalent to "the DUT's address-translation description".

An ideal vector of functions would be such that each and every one of the functions is of a general analytic form that can describe any device under test, by simply having different sets of coefficients for different devices under test. For  
10 example, if  $x'$  could be described, for the entire device under test area, for any device under test as:

$$x' = ax + by + cx^2 + d \sin(x \bullet y) + e \quad (4)$$

then only the coefficients  $a$ ,  $b$ ,  $c$ ,  $d$  and  $e$  need to be determined and entered into the real-time-display system. Additionally, such an ideal function would also  
15 allow the user to easily and methodologically find the coefficients for a given device under test.

In actuality, a vector of functions that can described the entire device under test area for any device under test is a vector of not-necessarily-linear, not necessarily-analytic functions. Therefor, a truly general implementation of such  
20 vector of translation function, could use a set of lookup tables (LUTs), one for each translated coordinate ( $x', y', z', w', v' \dots$ ), covering the entire device under test

area. But this "technique" results in huge tables and is very tedious to the person who needs to build them and is, therefore, impractical.

An address-translation description method, which cannot be mathematically defined as based on the above definition of ideal vector of functions, but indirectly answers the core requirements of such a vector and that can describe the entire area of every memory product is shown in the following model:

The device under test consists of two or more rectangular blocks identical in their width and height. Each block is a simple permutation of any of the rest of the blocks, in the sense that its address-translation can be described as the other block's address-translation, modified by a linear operation on the original value in a corresponding coordinate in the reference block:

$$g(x,y) = A \cdot f(ax + b, cy + d) + B \quad (5)$$

Where  $a$ ,  $b$ ,  $c$ ,  $d$ ,  $A$  and  $B$  are coefficients that are specific to each block and each translated coordinate component.

Note:

the above expression can intuitively be viewed as a combination of displacement,  $g(x,y) = f(x + d_x, y + d_y)$  and mirroring,  $g(x,y) + f(2m_x - x, 2m_y - y)$  - modified by a linear operation,  $A \cdot f + B$ .

With the above model, if the user can describe the reference block, the user can describe the entire device under test by simply providing sets of the coefficients  $a$ ,  $b$ ,  $c$ ,  $d$ ,  $A$  and  $B$  -in addition to the reference block description.

Describing the reference block is fundamentally the same as describing the entire device under test as discussed above, which previously could only be solved with extensive look up tables, except that the reference block with the above model is smaller than the device under test.

5           Such a reference block will be referred to herein as a *repeatable unit* or RU and a repeatable unit that cannot be further described by smaller RUs, using the above described model is defined herein as the *smallest repeatable unit* or SRU. For the sake of consistency and simplicity a reference block will always be a block that starts at buffer coordinate (0,0).

10           By partitioning the device under test into SRUs the above model can be extended beyond "ordinary" RUs. Empirically, a smallest repeatable unit is always much smaller in size than the device under test to which it belongs (in the order of 256 x 256 vs. 16384 x 16384 or even 16 x 512 vs. 16384 x 65536). Therefore, a substantially smaller "SRU" lookup table (or a vector of look up  
15           tables) can be used to describe any smallest repeatable unit without incurring the excessive memory penalty discussed above with respect to conventional lookup tables.

20           In the foregoing model (e.g., equation 5) the x and y variables are supplied from the two-dimensional failmap. These are the buffer coordinates of the cell for which a physical address is desired. The coefficients "b" and "d", respectively, commonly represent the horizontal and vertical displacement of a given block from the reference block, but can have values other than the width and height of

the reference block, respectively, when such degree of freedom can better serve the user of this inventive method.

The coefficients "a" and "c", respectively, represent horizontal and vertical mirroring and/or stretching of a given block from the reference block. If no mirroring is involved, then the coefficient value is a positive number. If a block is mirrored, then the coefficient value is negative. If no stretching is applied to the block then the coefficient value is either +1 or -1. A coefficient value other than +1 or -1 would stretch the block.

The coefficient A performs an "amplification" or "pattern reversal" operation or both. In most cases the value of A is either +1 or -1. However, this model does not restrict the value of A, when such degree of flexibility can better serve the user of this inventive method.

When  $A = +1$  the function is not altered. Positive values other than +1, amplify the values obtained from the reference block. Negative numbers amplify and/or reverse numerical patterns in the block. The variable B represents the linear displacement of the values taken from the look up table within each of the blocks.

The SRU look up tables comprise a collection of two-dimensional matrices, such that:

$$(x', y', z', w', v', \dots) = (I_{yx}^{x'}, I_{yx}^{y'}, I_{yx}^{z'}, I_{yx}^{w'}, I_{yx}^{v'}, \dots) \quad (6)$$

for all  $0 < x < w$  and  $0 < y < h$ . Where  $w, h$  are the width and height of the smallest repeatable unit, respectively;  $l_{xy}^{x'}$  is the element at column  $x$ , row  $y$  in the matrix  $[L^{x'}]$ ; and  $[L^{x'}]$  is a matrix of dimension  $h \times w$ , describing the  $x'$  component of the translated coordinate.

5 Or, in a shorter notation:

$$(x', y', z', w', v', \dots) = \vec{l}_{yx} \quad (7)$$

The above vector of functions in equation 7 has the ability to practically describe any smallest repeatable unit. Therefore, equation 7 and the above model describe the entire device under test area in terms of the smallest repeatable unit.

10 Equation 5 and the model can be used in a "flat" straightforward method, a recursive method or a combination of both.

The "Flat" (and straightforward) method includes processes of identifying a smallest repeatable unit (e.g., the top-left SRU), using a vector of  $n$  lookup tables (where " $n$ " is the dimension of a translated coordinate) and describing the device under test as  $N \times M$  smallest repeatable units (where  $N = W/w$  and  $M = H/h$ ,  $W$  and  $H$  are the width and height of the DUT, respectively, and  $w$  and  $h$  are the width and height of the SRU, respectively).

15 The flat method has the advantage that it simply requires specifying  $N \times M$  vectors, where each vector includes  $n$  sets of the 6 coefficients:  $a, b, c, d, A$  and  $B$  (each set of coefficients is not necessarily identical to any of the rest).

20



The disadvantage of the flat approach is that the user has to find (and enter)  $N \times M \times n$  sets of coefficients where each set has 6 coefficients. Therefore, if the smallest repeatable unit is small enough (a very desirable property),  $N \times M$  could reach the order of hundreds of thousands. For example, a 1Gb memory product with an 8Kb SRU will have  $N \times M = 1\text{Gb}/8\text{Kb} = 154,112$ . Referring to the same example, the variable "n" is usually at least 3, which would result in 462,336 sets of coefficients. Thus, the flat method is somewhat impractical.

The recursive method includes the following processes. First, a smallest repeatable unit (e.g., the top-left SRU) is identified using a vector of n lookup tables (where "n" is the dimension of a translated coordinate). A next-level repeatable unit,  $RU_0$ , is defined as  $N_0 \times M_0$  smallest repeatable units (where  $N_0 = W_0/w$  and  $M_0 = H_0/h$ ). The variables  $W_0$  and  $H_0$  are the width and height of  $RU_0$ , respectively, and  $w$  and  $h$  are the width and height of the smallest repeatable unit, respectively. The  $N_0 \times M_0$  vectors are then specified, again each vector includes n sets of 6 coefficients: a, b, c, d, A and B. Then, the next-level repeatable unit,  $RU_1$  is identified as  $N_1 \times M_1$   $RU_0$ 's, using the same approach used to describe  $RU_0$ . This process is again repeated to describe  $RU_2$  and so on, until the entire DUT is described as  $N_i \times M_i$  of  $RU_{i-1}$ 's. The variables  $N_0, N_1, \dots, N_i$  and  $M_0, M_1, \dots, M_i$  must be natural numbers.

Because of its recursive nature, this approach requires many less sets of coefficients. The disadvantage is that the recursive method increases the difficulty of partitioning and sub-partitioning the device because there are multiple ways to

recursively partition the device under test. However, the ability to partition the device under test in various ways actually increases the flexibility of the method. The recursive method is practical and can be implemented inexpensively.

The recursive partitioning and its advantage over the flat method will be further explained using the following exemplary 256Mb device under test having a value of  $i$  (i.e. number of levels of repeatable units- exclusive of the smallest repeatable unit) equal to 5 ( $i = 0$  to 4). The layout/partitioning of the device under test is as follows. The DUT has 2  $RU_4$ s; each  $RU_4$  has 2  $RU_3$ s; each  $RU_3$  has 2  $RU_2$ s; each  $RU_2$  has 32  $RU_1$ s; each  $RU_1$  has 4  $RU_0$ s; and each  $RU_0$  has 4 SRUs.

This amounts to only  $2 + 2 + 2 + 32 + 4 + 4 = 46$  vectors of sets of coefficients. To the contrary, using the flat method, would require specifying  $2 \cdot 2 \cdot 2 \cdot 32 \cdot 4 \cdot 4 = 4096$  vector of sets of coefficients.

Therefore, with the invention, every point  $(x,y)$  in an  $i$ th-level repeatable unit (except for the smallest repeatable unit) can be translated as follows:

$$f_i^x(x, y) = A_i^x \cdot f_{i-1}^x(a_i^x x + b_i^x, c_i^x y + d_i^x) + B_i^x$$

$$f_i^y(x, y) = A_i^y \cdot f_{i-1}^y(a_i^y x + b_i^y, c_i^y y + d_i^y) + B_i^y$$

$$f_i^z(x, y) = A_i^z \cdot f_{i-1}^z(a_i^z x + b_i^z, c_i^z y + d_i^z) + B_i^z \quad (8)$$

$$f_i^w(x, y) = A_i^w \cdot f_{i-1}^w(a_i^w x + b_i^w, c_i^w y + d_i^w) + B_i^w$$

$$f_i^v(x, y) = A_i^v \cdot f_{i-1}^v(a_i^v x + b_i^v, c_i^v y + d_i^v) + B_i^v$$

Values must be assigned to  $a, b, c, d, A$  and  $B$ - for every level,  $i$ , and for every translated coordinate in the vector  $(x', y', z', w', v' \dots)$ . This is usually an intuitive and relatively easy task, especially when considering that the variable  $A$  has usually the value of 1 or -1; the variable  $a$  has usually the value of either 1 or -1. The variable  $c$  has usually the value of either 1 or -1; the variables  $b$  and  $d$  are usually proportional to the width and height of the repeatable unit, respectively.

Thus, the main "challenge" for the user is to find the  $B$  coefficients.

The process for finding those sets of coefficients can include taking any 6  $(x, y)$  points in the repeatable unit to be described, taking the corresponding points in the reference repeatable unit and assign them in the 6 equations of the form of equation 5 ;  $g(x, y) = A \cdot f(ax + b, cy + d) + B$ . This results in a set of 6 equations

of 6 variables which are solved by numerical analysis methods, for example, using a computer program.

With the following example shown in Table 1, a repeatable unit includes 4 smallest repeatable units and only one translated coordinate.

5 (0,0) (15,0)

0, 0, 1, 1, 2, 2, 3, 3	15, 15, 14, 14, 13, 13, 12, 12
4, 4, 5, 5, 6, 6, 7, 7	11, 11, 10, 10, 9, 9, 8, 8
15, 15, 14, 14, 13, 13, 12, 12	0, 0, 1, 1, 2, 2, 3, 3
11, 11, 10, 10, 9, 9, 8, 8	4, 4, 5, 5, 6, 6, 7, 7

10 (0,3) (15,3)

Table 1

The bottom-left quarter is mirrored twice - both in the X axis and in the Y axis. The numbers in the table represent one-dimension translated coordinate, although mirroring is not limited to one dimension because their values are dependent on both x and y.

The variable X is defined as the value derived from the look up table for the original smallest repeatable unit ("first level translation"). The variable  $X^0$  is the value derived from (x, y) for the next level repeatable unit. The value  $X^1$  is the value derived from (x, y) for the second level repeatable unit, and so on.

20 While any  $X^0$  value, for every point (x,y), in the top-left repeatable unit is identical to X by definition - the  $X^0$  value is determined according to the following functions in the other quarters (or RUs):

Bottom-left -  $f_{x0}(x, y) = 1 \cdot f_x(7 - x, 3 - y) + 8$ ;

Top-right -  $f_{x0}(x,y)=1 \cdot f_x(15-x,1-y)+8$ ; and

Bottom-right -  $f_{x0}(x,y)=1 \cdot f_x(x-8, y-2)+0$ .

While the mathematical methodology of the invention is described above, the invention can be embodied in any number of different types of systems and executed in any number of different ways, as would be known by one ordinarily skilled in the art. For example, as illustrated in Figure 1, a typical hardware configuration of an information handling/computer system in accordance with the invention preferably has at least one processor or central processing unit (CPU) 100. The CPU 100 is interconnected via a system bus 101 to a random access memory (RAM) 102, read-only memory (ROM) 103, input/output (I/O) adapter 104 (for connecting peripheral devices such as disk units 105 and tape drives 106 to the bus 101), communication adapter 107 (for connecting an information handling system to a data processing network) user interface adapter 108 (for connecting a keyboard 109, microphone 110, mouse 111, speaker 112 and/or other user interface device to the bus 101), and display adapter 113 (for connecting the bus 101 to a display device 114).

Figure 2 illustrates a flow chart of a method used for implementing the invention. The method includes 3 principle stages (blocks 20, 21, 22). The user (or a related professional) starts by describing the entire DUT using SRUs and the  $A \cdot f(ax+b,cy+d)+B$  method, and finding the values of all coefficients in block 20. More specifically, in Figure 3, the user finds the smallest repeatable unit of a device under test in block 30. Then, in block 31 a determination is made whether

the entire device under test can be described using the  $A \bullet f(ax + b, cy + d) + B$  method. If it cannot be described using the  $A \bullet f(ax + b, cy + d) + B$  method, the repeatable unit is not the smallest repeatable unit and processing returns to block 30, as illustrated in block 32.

5           If the entire device under test can be described using the above method, processing proceeds to block 33 where the next level of repeatable unit is created (preferably from less than 32 repeatable units) and the coefficients for each of the repeatable units (in terms of the top-left repeatable unit) are found. In block 34, it is determined whether the entire device under test has been described. If it has not  
10       been described, processing returns to block 33. If it has been described, processing proceeds to the end where the product description language file (PDL) can be edited, or the newly found information can be entered to the system in any acceptable way.

15           Figure 4 illustrates a flow chart of a software program for implementing the last stage of invention (as depicted in Figure 2 block 22). More specifically, in Figure 4, block 41, the computer program inputs and stores the coefficients for the RUs and the partitioning information generated in block 20 and entered in block 21. Then, in block 42 the program retrieves the x,y values for the buffer  
20       coordinate to be translated. Then in block 43 the program determines which next-lower-level RU contains the point to be translated. Then, in block 44 the program assigns the values x, y in the  $A \bullet f(ax + b, cy + d) + B$  formula, using the stored coefficients for the particular RU to obtain the translated method. Then in block

45 a determination is made as to whether that RU is the SRU. If not, the processing goes back to block 43 to obtain the value from a further lower-level RU. When the programs finally gets to the SRU, in block 46 the program returns the value obtained from the LUT, using the multiply-transformed buffer coordinate and assigning it recursively in all levels of RUs that contain the original point. At this point the program is ready to display, store and/or output the newly translated value.

As would be known by one ordinarily skilled in the art given this disclosure, a computer program in any suitable language can be prepared to execute the invention. For example, to accomplish the step described in Figure 2, block 21, the user could prepare the necessary information for the address translation by creating in a product description language (PDL) file, using any text editor. The format and grammar for such a file could, for example, have the following format:

- Every translated coordinate (i.e. row, column, DQ, etc.) could be described in its own section. The section could start with the line:

*<BUF2PHYS> coordinate-name*

and end with the line:

*<END-BUF2PHYS>*

*coordinate-name* is the title that the user wants to be displayed on the RTD when reporting the value of the translated coordinate.

- Following the start of the coordinate section, the smallest repeatable unit could be described with reference to a look up table. The smallest repeatable unit description has its own section (within the coordinate section), starting with the line:

5                   <STARTLUT>

and ending with the line:

                  <ENDLUT>

Note:

At times, a smallest repeatable unit address-translation pattern is simple enough that it can be described using a relatively simple algebraic expression, thus saving the memory required for a look up table.

Therefore, an alternative way for describing a smallest repeatable unit is as follows:

10                   <STARTSRU>

15                   S = expression

                  <ENDSRU>

where *expression* is any mathematical expression that takes *x* and *y* as arguments (e.g.  $3x + 7 - (y \ll 4) \% 5$ ).

- Following the start of the look up table section, the maximum value for the translated coordinate could be specified (this may be done to optimize memory use) in a separate line:



.MAXVALUE *integer*

- In the next line, the look up table dimension could be specified:

.LUTSIZE *width x height*

- Then, one or more lines that set the actual entries in the look up table,  
5 could take one of the following forms:

*offset: (number, number, number,...) x times op modifier*

which is interpreted as follows: "starting at offset *offset* in the array, **set**  
the numbers specified between the parenthesis and then repeat this process  
*times-1* times, but each time modify the respective number by *modifier*,  
10 using the operator *op*". *op* can be any known algebraic operator (linear,  
Boolean and/or modulus) or

*offset: [src-offset, count] x times op modifier*

which is interpreted as follows: "**copy** to offset *offset* in the array *count* x  
(*times-1*) entries, each *count* entries being modified by *modifier*, using the  
15 operator *op*".

- After the end of the smallest repeatable unit section, there can be any  
number of repeatable unit description *statements*. Each subsequent  
statement describes the next-level repeatable unit in terms of the already

defined, one-level-lower repeatable unit. For example, the statements could take the following form:

$$\begin{aligned}
 R_j = & \{ [R_i(x, y)], \dots, [A_{m0}R_i(a_{m0}x+b_{m0}, c_{m0}y+d_{m0})+B_{m0}] \} \\
 & \{ [A_{01}R_i(a_{01}x+b_{01}, c_{01}y+d_{01})+B_{01}], \dots, [A_{m1}R_i(a_{m1}x+b_{m1}, c_{m1}y+d_{m1})+B_{m1}] \} \\
 & \cdot \\
 & \cdot \\
 & \cdot \\
 & \{ [A_{0n}R_i(a_{0n}x+b_{0n}, c_{0n}y+d_{0n})+B_{0n}], \dots, [A_{mn}R_i(a_{mn}x+b_{mn}, c_{mn}y+d_{mn})+B_{mn}] \} ;
 \end{aligned}$$

A statement can span over multiple lines. In fact, there is no significance to line breaks - they are simply considered a space. A statement should start with the literal *R* (or *DUT*), followed a number and an equal sign (=), and it should end with a semicolon (;). A statement may include one or more rows, denoted by enclosing braces ( { ... } ). Every row should contain at least one **term**. A term must be enclosed by square brackets ([...]). The term defines a region in the current repeatable unit in terms of one-level-lower repeatable unit. The region is a rectangle, equal in width and height to the width and height of the reference repeatable unit. The region's position is determined by the term's position in the statement (therefore, it is preferable for the user to try to visually format a statement, to match the physical RUs organization). Each term should be of the form  $AR_i(ax+b, cy+d) + B$ . The coefficients *A*, *B*, *a*, *b*, *c* and *d* are the same described in the mathematical model, above. The top-left term preferably has the coefficients always set to  $A=1, B=0, a=1, b=0, c=1, d=0$ , because the top-left repeatable unit is preferably the reference repeatable unit and is

equal to itself ,by definition. The last statement that appears in the coordinate section describes the entire device under test rectangle, regardless whether it starts with R or DUT, but for readability it is preferable to use the keyword DUT in the last statement (and only in the last statement).

- As is customary in user-friendly text-based description languages, comments, comment lines and empty lines should be supported. Thus, anything that comes after a comment symbol (; or # or//) is simply ignored.

An exemplary product description language file for a device under test follows.

```
<BUF2PHYS> column // column (or x'] LUT for the single SRU(256x256).
<STARTLUT>
.MAXVALUE 63
.LUTSIZE 256x256
0:      (0,0,0,0) x64 +1
        [0, 256] x256 +0
<ENDLUT>
// RU0 is made out of 2x2 SRUs {no mirroring, just displacement}.
// This makes RU0 of size 512x512=256K
R0 = {[S(x,y)]      [S(x-256,y)+256/4]}
      {[S(x,y-256)] [S(x-256, y-256)+256/4]};

// RU1 is made out of 4x1 RU0s (no mirroring, just displacement).
// This makes RU1 of size 2Kx512=1M
R1  = {[R0(x,y)] [R0(x-512,y)+512/4] [R0(x-2*512,y)+2*512/4] [R0(x-
3*512,y)+3*512/4]};
```

```
// RU2 is made out of 2x16 RU1s - right half is mirror of left one.
// This makes RU2 of size 4Kx8K=32M
```

```
R2=      {[R1 (x,y)]      [R1 (-x+4095, y)]}
          {[R1 (x,y-1*512)] [R1 (-x+4095,y-1*512)]}
          {[R1 (x,y-2*512)] [R1 (-x+4095,y-2*512)]}
          {[R1 (x,y-3*512)] [R1 (-x+4095,y-3*512)]}
          {[R1 (x,y-4*512)] [R1 (-x+4095,y-4*512)]}
          {[R1 (x,y-5*512)] [R1 (-x+4095,y-5*512)]}
          {[R1 (x,y-6*512)] [R1 (-x+4095,y-6*512)]}
          {[R1 (x,y-7*512)] [R1 (-x+4095,y-7*512)]}
          {[R1 (x,y-8*512)] [R1 (-x+4095,y-8*512)]}
          {[R1 (x,y-9*512)] [R1 (-x+4095,y-9*512)]}
          {[R1 (x,y-10*512)] [R1 (-x+4095,y-10*512)]}
          {[R1 (x,y-11*512)] [R1 (-x+4095,y-11*512)]}
          {[R1 (x,y-12*512)] [R1 (-x+4095,y-12*512)]}
          {[R1 (x,y-13*512)] [R1 (-x+4095,y-13*512)]}
          {[R1 (x,y-14*512)] [R1 (-x+4095,y-14*512)]}
          {[R1 (x,y-15*512)] [R1 (-x+4095,y-15*512)]};
```

```
// RU3 is made out of 2x1 RU2s - the right half produced by a simple displacement
// This makes RU3 of size 8Kx8K=64M
R3= {[R2(x,y)] [R2(x-4096, y)]};
```

```
// RU4 is made out of 2x1 RU3s - the right half is a mirror of the left one.
// This makes RU4 of size 16Kx8K=128M
R4= {[R3(x,y)] [R3(-x+(16*1024-1), y)]};
```

```
// DUT is made out of 1x2 RU4s - the bottom half is a mirror of the top one.
// This makes DUT of size 16Kx16K=256M
```

```
DUT=      {[R4(x,y)]}
          {[R4(x,-y+16383)]};
<END-BUF2PHYS>
```

```
<BUF2PHYS> row // row (or y') LUT for the single SRU.
<STARTLUT>
.MAXVALUE 8191
.LUTSIZE 256x256
```

```

0: (8191}      x256
    [0, 2567 x256 -1
<ENDLUT>
<END-BUF2PHYS>

5  <BUF2PHYS> DQ // DQ (or z') LUT for the single SRU. .MAXVALUE 4
    .LUTSIZE 256x256
0:      (0,1,2,3) x64 +0
        [0, 256} x256 +0
<ENDLUT>
10 <END-BUF2PHYS>

```

Step 3 in the inventive method, as indicated in Figure 2, block 22 and further described in Figure 4 could be, for example, implemented in the C++ language, using an object oriented approach as follows

```

////////////////////////////////////
15 // this class represents a single RU term
    // (the constants in: Af(ax+b,cy+d)+B)
    class CRUTerm
    {
    private:
20         long a, b, c, d, A, B;      // the famous RU coefficients.
    public:
        CRect r;                      // bounds of RU rectangle in absolute
        coords.
        CRUTerm();                    // constructor
25         ~CRUTerm();                 // destructor
        int Parse(String& rExpr);     // knows how to translate a text string
        // into coefficients.
        void GetCoefficients (int & ra, int & rc, int & rc, int & rd, int
        & rA, int & rB) const;

```

```
};
```

```
////////////////////////////////////////////////////////////////
```

```
// this class represents the SRU (implemented by either a LUT or a  
// mathematical expression)
```

```
5 class CSRU
```

```
{
```

```
private:
```

```
    bool valid;          // either LUT or SRU exp has to be valid.
```

```
    int dataTypeSize;    // size (in bytes) of a LUT element.
```

```
10
```

```
    bool useLUT;         // tells whether use LUT or exp for SRU.
```

```
    void *pLUT;          // SRU: 2 dmnsnl packed-array byt ushorts, ultongs.
```

```
    CRect r;             // bounds of the RU rectangle in buffer coord.
```

```
public:
```

```
    CSRU();              // constructor
```

```
15
```

```
    ~CSRU();             // destructor
```

```
    int Parse (String& expr); // know how to trans descrip txt into
```

```
//data members.
```

```
    ULONG GetPhysVal(ULONG x, ULONG y) const; // does actual address-
```

```
//translation
```

```
20
```

```
    int GetTblElemSize () const { return dataTypeSize; };
```

```
    const CRect & Bounds() const {return r;};
```

```
};
```

```
////////////////////////////////////////////////////////////////
```

```
// this class represents a single RU (excluding the SRU)
```

```
25
```

```
class CRU
```

```
{
```

```
private:
```

```
    CArray aTerms;       // dynamic array of all terms describing
```

```
RU(n) as func of RU(n-1).
```

```
30
```

```
    CRect r;             // bounds of the RU rect. in buffer coord.
```

```
public:
```

```
    CSRU *pSRU;          // only R0 will use this pointer.
```

```

        CRU *pPrev;          // ptr one-level-lower RU (def. current one).
        CRU();                // constructor
        ~CRU();               // destructor

int Parse(String& expr); // knows how to translate txt string into terms.
5  ULONG GetPhysVal{ULONG x, ULONG y) const; // does actual address transl
    const CRect& Bounds() const {return r;};
};

////////////////////////////////////
////////////////////////////////////

10 //      this class completely encapsulates a single physical coordinate
    //      (e.g. column address, row address, DQ, etc.)

    class CBufToPhys
    {
    private:
15         CSRU *pSRU;        // pointer to the SRU object.
        CArray aRU;          // array of arrays all RUs, including DUT, but
                                excluding SRU.
        public:
        String name;          // coordinate title.
20         CBufToPhys();      // Constructor
        ~BufToPhys();         // destructor

int Parse(istream&); // knows how to trans coord sect. into CbufToPhys obj.
    ULONG GetPhysVal(ULONG x, ULONG y) const; // does the actual address-
        translation
25 };

```

Because of the recursive nature of this model, the real-time-display system software only needs to call the corresponding CbufToPhys object's member function GetPhysVal (x, y) in order to obtain the physical value of a given buffer

coordinate (x, y). The function CbufToPhys::GetPhysVal (x, y) simply calls  
 CRU:: GetPhysVal (x, y), which recursively calls the one-level-lower object's  
 CRu::Get PhysVal (x, y) and so on until the SRU's value is obtained and returned  
 as follows:

```

5  ULONG CRU::GetPhysVal(ULONG x, ULONG y) const
    {
        CPoint pt(x,y); // simply convert {x,y} to CPoint for PtInRect().

        int lastRow = aTerms.GetUpperBound();
        int lastTerm;
10  CArray *pCurRow;
        CRUTerm *pCurTerm;
        int i, j;    // row and column iterators, respectively
        for (i=0; i<=lastRow; i++)
        {
15          pCurRow = (CArray *)aTerms[i];
            lastTerm = pCurRow->GetUpperBound();
            for (j=0; j<=lastTerm; j++)
            {
20              pCurTerm = (CRUTerm *) ((*pCurRow) [j]);
                if {pCurTerm->r.PtInRect(pt)}
                {
                    i = lastRow + 1; // just so that the outer loop will break, too.
                    break;
                }
25          }
        }

        int a, b, c, d, A, B;
        pCurTerm->GetCoefficients(a, b, c, d, A, B);

        if (pPrev == NULL)
30          return A*(pSRU->GetPhysVal(a*x+b, c*y+d)) + B;
  
```



```

else
    return A*(pPrev->GetPhysVal(a*x+b, c*y+d)) + B;
}

```

Therefore, as shown above, a device under test (e.g., memory device) is tested for defects and a two-dimensional failmap is produced on a real time display. In order to identify the physical (electrical) location of a given defective element of the device under test, the two-dimensional coordinate of the failmap must be translated into an n-dimensional physical location (e.g., word-line, bit-line, DQ, etc.).

Conventionally, a programmer would prepare an algorithm or look up table relating to the entire device under test to perform the address translation. However, with the invention, the user (without the aid of a programmer) only needs to prepare a lookup table relating to the smallest repeatable unit of the device under test. In addition, the user supplies coefficients relating to linear operation on the lookup table values and horizontal and vertical mirroring and displacement from the reference block (as well as any additional required features) and the invention applies the look up table to all other smallest repeatable units to perform the address translation for the entire device under test. In addition, the recursive nature of the invention requires substantially reduced input from the user by defining larger and larger repeatable units.

Thus, with the invention, only sets of 6 coefficients and a look up table and the recursive partitioning information are required from the user and the assistance, design time, debugging time and other costs associated with conventional customized address translation programs are avoided.

Further , with the invention new products can be described and loaded to the system while the system is running and without rebooting it. Also, the process of finding and entering the information described above (coefficients, LUTs and partitioning) can be further automated, effectively reducing the time required to describe a product even more.

5           The invention is applicable to memory tests and memory design, any process, application or environment that requires translation of values obtained from a point located on 2-dimensional plane that have a repeatable pattern created by mirroring and/or displacement and/or linear operation. Even simple systems with  $N = 1$  (i.e. one dimension only) could benefit from the invention.

## 10       **II. Additional Embodiments**

While the foregoing translates buffer coordinates into physical addresses for all existing memory products, there are some intricate memory designs that force the user to either use larger than typical lookup tables and/or fewer than typical recursion levels. This generally results in larger than typical memory consumption and laborious user input.

15           An optimized solution to this problem is to describe - in selected recursion levels - repeatable units in terms of a reference repeatable unit, using the formula:

$$\text{MAP}[f(ax+b, cy+d)]$$

instead of:

$$A*f(ax+b, cy+d) + B$$

MAP is a scalar translation table comprising key-value pairs. Both the key and the value are integers. For example, if the expression  $f(ax+b, cy+d)$  for a reference repeatable unit can have only the following limited set of values: 12, 13, 14, 15, then a MAP for another repeatable unit in that recursion level could be as follows:

5

12	14
13	12
14	13
15	15

10

It is important to note that while it is possible to use the MAP formula in all recursion levels for a particular DUT type, or use the MAP formula in some recursion levels for all DUT types, it is generally not efficient to do so. In fact, for the vast majority of DUT types, using the  $A*f(ax+b, cy+d) + B$  formula exclusively is optimal. The MAP formula should be used sparingly, in cases where it is clear that such use will significantly reduce system memory use and/or the user input.

An example of this embodiment is a DUT of 32Kx8K (256MB) with the following DQ layout:

	<----- 32K ----->				
5	15	11	11	15	A
	0	4	4	0	
	13	9	9	13	
	2	6	6	2	
10	9	13	13	9	
	6	2	2	6	
	11	15	15	11	
	4	0	0	4	
15	4	0	0	4	8K
	11	15	15	11	
	6	2	2	6	
	9	13	13	9	
20	2	6	6	2	
	13	9	9	13	
	0	4	4	0	
	15	11	11	15	V
25					

In this example, each set of 4 numbers enclosed represents a repeating pattern in the block enclosing it: In the top left block the first, fifth, ninth, etc. lines (512 such lines) have a DQ value of 15 (8192 such columns), the second, sixth, tenth, etc. (512 such lines) have a DQ value of 0 (8192 such columns), and so on.

Using the previous embodiment, the DQ address translation for the entire DUT involves only 3 recursion levels. A LUT of 16K x 1 (16384x1):

<STARTLUT>

.MAXVALUE 15

.LUTSIZE 16384x1

0: (15) x8192 0

(11) x8192 0

<ENDLUT>

RU0 which is made from 4096 LUTs vertically displaced into 16384x4096:

$$\begin{aligned}
 R0 = \{ & [S(x, \quad y-0) - 0] \} \\
 & \{ [S(-x+16383, y-1) - 11] \} \\
 & \cdot \\
 & \cdot \\
 & \{ [S(-x+16383, y-4094) - 0] \} \\
 & \{ [S(x, \quad y-4095) - 11] \};
 \end{aligned}$$

(total of 4096 such lines)

And DUT, which is made from 4 RU0's displaced and mirrored about the x and y axis:

$$\begin{aligned}
 DUT = \{ & [R0(x, y)] \quad [R0(-x+2*16384-1, y)] \} \\
 & \{ [R0(x, -y+2*4096-1)] \quad [R0(-x+2*16384-1, -y+2*4096-1)] \};
 \end{aligned}$$

RU0 is relatively huge (only a quarter of the entire DUT) and involves 4,096 different sets of coefficients.

However, in this embodiment, using the same LUT, much smaller RU's can be defined:

1) A LUT of 16K x 1

2) RU0 is made from 4 LUTs (16384x1) vertically displaced into 16384x4.

$$\begin{aligned}
 R0 = \{ & [S(x, y)] \} \\
 & \{ [S(-x+16383, y-1) - 11] \} \\
 & \{ [S(x, \quad y-2) - 2] \} \\
 & \{ [S(-x+16383, y-3) - 9] \}
 \end{aligned}$$

3) RU1 is made from 512 RU0's (16384x4) vertically displaced into 16384x2048.

$$RU1 = \{ [R0(x, y)] \}$$

001210-5332460

{ [R0 (x,y-4)] }

{ [R0 (x,y-8)] }

.

.

.

{ [R0 (x,y-2040)] }

{ [R0 (x,y-2044)] }

4) RU2 is made from 2 RU1's (16384x2048) horizontally mirrored & displaced into 32Kx2K.

RU2 = { [R1 (x,y)] [R1 (-x+32767,y)] }

5) RU3 is made from 2 RU2's (32Kx2K) vertically displaced into 32Kx4K.

MAP3\_0\_1 = 15:9, 11:13, 0:6, 4:2, 13:11, 9:15, 2:4, 6:0

RU3 = { [R2 (x,y)] }

{MAP3\_0\_1 [R0 (x,y-2048)] }

6) DUT is made from 4 RU3's displaced and mirrored about the x & y axis

DUT={ [R0 (x,y)] [R0 (-x+2\*16384-1,y)] }

{ [R0 (x,-y+2\*4096-1)] [R0 (-x+2\*16384-1,-y+2\*4096-1)] };

The first and last level are identical in both embodiments. The difference is two extra recursion levels that reduce the number of coefficients sets from 4096 to 4+512+2+2 = 520. In fact, because of the flexibility of the "MAP" embodiment it is possible to define an even smaller RU1 and recursively iterate to bigger RU's, resulting in less than 100 sets of coefficients. This saves both system memory and user input.

Figure 5 is a flow chart of a method used for implementing the invention and is similar to Figure 2 except that the "MAP" embodiment is now illustrated. More specifically, this embodiment includes 3 principal stages (blocks 50, 51, 52). The user (or

a related professional) starts by describing the entire DUT using SRUs and the  $A*f(ax+b,cy+d)+B$  and/or  $MAP((ax+b,cy+d))$  method, and finding the values of all coefficients in block 50. More specifically, in Figure 6 (which corresponds to Figure 3), the user finds the smallest repeatable unit of a device under test in block 60. Then, in block 61 a determination is made whether the entire device under test can be described using the  $A*f(ax+b,cy+d)+B$  and/or  $MAP((ax+b,cy+d))$  method. If it cannot be described using the  $A*f(ax+b,cy+d)+B$  and/or  $MAP((ax+b,cy+d))$  method, the repeatable unit is not the smallest repeatable unit and processing returns to block 60, as illustrated in block 62.

If the entire device under test can be described using the above method, processing proceeds to block 63 where the next level of repeatable unit is created (preferably from less than 62 repeatable units) and the coefficients for each of the repeatable units (in terms of the top-left repeatable unit) are found. In block 64, it is determined whether the entire device under test has been described. If it has not been described, processing returns to block 63. If it has been described, processing proceeds to the end where the product description language file (PDL) can be edited, or the newly found information can be entered to the system in any acceptable way.

Figure 7 (which corresponds to Figure 4) illustrates a flow chart of a software program for implementing the last stage of invention (as depicted in Figure 5 block 52). More specifically, in Figure 7, block 70, the computer program inputs and stores the coefficients for the RUs and the partitioning information generated in block 50 and entered in block 51. Then, in block 71 the program retrieves the x,y values for the buffer coordinate to be translated. Then in block 72 the program determines which next-lower-

level RU contains the point to be translated. Then, in block 73 the program assigns the values x, y in the  $A*f(ax+b, cy+d)+B$  and/or  $MAP((ax+b, cy+d))$  formula, using the stored coefficients for the particular RU to obtain the translated method. Then in block 74 a determination is made as to whether that RU is the SRU. If not, the processing goes back to block 72 to obtain the value from a further lower-level RU. When the programs finally gets to the SRU, in block 75 the program returns the value obtained from the LUT, using the multiply-transformed buffer coordinate and assigning it recursively in all levels of RUs that contain the original point. At this point the program is ready to display, store and/or output the newly translated value. Thus, the invention uses  $MAP(ax+b, cy+d)$  instead of  $A*f(ax+b, cy+d) + B$ , when it saves either system memory or user input or both.

While the invention has been described in terms of preferred embodiments, those skilled in the art will recognize that the invention can be practiced with modification within the spirit and scope of the appended claims.



## CLAIMS

Having thus described our invention, what we claim as new and desire to secure by Letters Patent is as follows:

1. A method for determining the failure location of units on redundant unit type semiconductor devices comprising:
  - determining the address of the failure; and
  - determining the physical location of the failure by applying a set of displacement and mirror factors to the address.
2. The method in claim 1, wherein said address comprises a two-dimensional failmap address, said physical location comprises a n-dimensional electrical address of said failure location and n comprises a natural number.
3. The method in claim 1, further comprising:
  - identifying repeatable units of said units;
  - preparing a look up table for translating buffer coordinates of a reference unit of said repeatable units;
  - displacing information from said look up table to correspond to said repeatable units; and

modifying results of said displacing by a linear operation or a scalar translation  
table comprising key-value pairs.

4. The method in claim 3, wherein said displacing includes mirroring said  
information from said look up table to correspond to said repeatable units

5. The method in claim 3, wherein said reference unit comprises a smallest  
repeatable unit.

6. The method in claim 5, further comprising:  
identifying a first level of repeatable units, having a size larger than said smallest  
repeatable unit;  
identifying a second level of repeatable units, having a size larger than said first  
level of repeatable units; and  
recursively displacing said information from said look up table to correspond  
respectively to said smallest repeatable units, said first level of repeatable units and  
second level of repeatable units.

7. The method in claim 3, wherein said displacing and modifying comprise  
translating said buffer coordinates using at least one of the following functions:

$$g(x,y) = A \bullet f(ax + b, cy+d) + B; \text{ and}$$

$$g(x,y) = \text{MAP}(ax + b, cy + d)$$

5 wherein variable A comprises one of an amplification and pattern reversal value,  
6 variable B comprises a linear displacement of said information from said look up table,  
7 variable b comprises a horizontal displacement from said reference unit, variable d  
8 comprises a vertical displacement from said reference unit, variable a comprises  
9 horizontal mirroring, variable c comprises vertical mirroring, and MAP is a scalar  
10 translation table comprising key-value pairs.

1 8. A method for translating address buffer coordinates for a device under test having  
2 two or more similar repeatable units, said method comprising:

3 identifying a repeatable unit of said repeatable units;  
4 preparing a look up table for translating buffer coordinates of a reference unit of  
5 said repeatable units;  
6 displacing information from said look up table to correspond to said repeatable  
7 units; and  
8 modifying results of said displacing by a linear operation or a scalar translation  
9 table comprising key-value pairs.

1 9. The method in claim 8, wherein said displacing includes mirroring said  
2 information from said look up table to correspond to said repeatable units

1 10. The method in claim 8, wherein said reference unit comprises a smallest  
2 repeatable unit.

1 11. The method in claim 10, further comprising:  
2 identifying a first level of repeatable units, having a size larger than said smallest  
3 repeatable unit;  
4 identifying a second level of repeatable units, having a size larger than said first  
5 level of repeatable units; and  
6 recursively displacing said information from said look up table to correspond  
7 respectively to said smallest repeatable units, said first level of repeatable units and  
8 second level of repeatable units.

1 12. The method in claim 8, wherein said displacing and modifying comprise  
2 translating said buffer coordinates using at least one of the following functions:

3 
$$g(x,y) = A \cdot f(ax + b, cy + d) + B; \text{ and}$$

4 
$$g(x,y) = \text{MAP}(ax + b, cy + d)$$

5 wherein variable A comprises one of an amplification and pattern reversal value,  
6 variable B comprises a linear displacement of said information from said look up table,  
7 variable b comprises a horizontal displacement from said reference unit, variable d  
8 comprises a vertical displacement from said reference unit, variable a comprises  
9 horizontal mirroring, variable c comprises vertical mirroring, and MAP is a scalar  
10 translation table comprising key-value pairs.



6 a unit for recursively displacing said information from said look up table to  
7 correspond respectively to said smallest repeatable units, said first level of repeatable  
8 units and second level of repeatable units.

1 17. The computer system in claim 15, wherein said unit for displacing and said unit  
2 for modifying comprises a unit for translating said buffer coordinates using at least one of  
3 the following functions:

$$g(x,y) = A \bullet f(ax + b, cy+d) + B; \text{ and}$$

$$g(x,y) = \text{MAP}(ax + b, cy + d)$$

6 wherein variable A comprises one of an amplification and pattern reversal value,  
7 variable B comprises a linear displacement of said information from said look up table,  
8 variable b comprises a horizontal displacement from said reference unit, variable d  
9 comprises a vertical displacement from said reference unit, variable a comprises  
10 horizontal mirroring, variable c comprises vertical mirroring, and MAP is a scalar  
11 translation table comprising key-value pairs.

1 18. A program storage device readable by machine, tangibly embodying a program of  
2 instructions executable by the machines to perform method steps for translating address  
3 buffer coordinates for a device under test having two or more similar repeatable units,  
4 said method comprising:

5 identifying a repeatable unit of said repeatable units;

6 preparing a look up table for translating buffer coordinates of a reference unit of  
7 said repeatable units;  
8 displacing information from said look up table to correspond to said repeatable  
9 units; and  
10 modifying results of said displacing by a linear operation or a scalar translation  
11 table comprising key-value pairs.

1 19. The program storage device in claim 18, wherein said displacing includes  
2 mirroring said information from said look up table to correspond to said repeatable units

1 20. The program storage device in claim 18, wherein said reference unit comprises a  
2 smallest repeatable unit.

1 21. The program storage device in claim 20, said method further comprising:  
2 identifying a first level of repeatable units, having a size larger than said smallest  
3 repeatable unit;  
4 identifying a second level of repeatable units, having a size larger than said first  
5 level of repeatable units; and  
6 recursively displacing said information from said look up table to correspond  
7 respectively to said smallest repeatable units, said first level of repeatable units and  
8 second level of repeatable units.

1 22. The program storage device in claim 18, wherein said displacing and modifying  
2 comprise translating said buffer coordinates using at least one of the following functions:

3 
$$g(x,y) = A \bullet f(ax + b, cy+d) + B; \text{ and}$$

4 
$$g(x,y) = \text{MAP}(ax + b, cy + d)$$

5 wherein variable A comprises one of an amplification and pattern reversal value,  
6 variable B comprises a linear displacement of said information from said look up table,  
7 variable b comprises a horizontal displacement from said reference unit, variable d  
8 comprises a vertical displacement from said reference unit, variable a comprises  
9 horizontal mirroring, variable c comprises vertical mirroring, and MAP is a scalar  
10 translation table comprising key-value pairs.



Parameter	Value
$\alpha$	0.05
$\beta$	0.05
$\gamma$	0.05
$\delta$	0.05
$\epsilon$	0.05
$\zeta$	0.05
$\eta$	0.05
$\theta$	0.05
$\iota$	0.05
$\kappa$	0.05
$\lambda$	0.05
$\mu$	0.05
$\nu$	0.05
$\xi$	0.05
$\omicron$	0.05
$\pi$	0.05
$\rho$	0.05
$\sigma$	0.05
$\tau$	0.05
$\upsilon$	0.05
$\phi$	0.05
$\chi$	0.05
$\psi$	0.05
$\omega$	0.05
$\Omega$	0.05
$\Theta$	0.05
$\Phi$	0.05
$\Psi$	0.05
$\Upsilon$	0.05
$\Sigma$	0.05
$\Pi$	0.05
$\Lambda$	0.05
$\Gamma$	0.05
$\Delta$	0.05
$\nabla$	0.05
$\propto$	0.05
$\partial$	0.05
$\int$	0.05
$\sum$	0.05
$\prod$	0.05
$\bigcap$	0.05
$\bigcup$	0.05
$\setminus$	0.05
$\oplus$	0.05
$\otimes$	0.05
$\oslash$	0.05
$\circ$	0.05
$\cdot$	0.05
$+$	0.05
$-$	0.05
$\times$	0.05
$\div$	0.05
$\frac{\partial}{\partial x}$	0.05
$\frac{\partial^2}{\partial x^2}$	0.05
$\frac{\partial^3}{\partial x^3}$	0.05
$\frac{\partial^4}{\partial x^4}$	0.05
$\frac{\partial^5}{\partial x^5}$	0.05
$\frac{\partial^6}{\partial x^6}$	0.05
$\frac{\partial^7}{\partial x^7}$	0.05
$\frac{\partial^8}{\partial x^8}$	0.05
$\frac{\partial^9}{\partial x^9}$	0.05
$\frac{\partial^{10}}{\partial x^{10}}$	0.05
$\frac{\partial^{11}}{\partial x^{11}}$	0.05
$\frac{\partial^{12}}{\partial x^{12}}$	0.05
$\frac{\partial^{13}}{\partial x^{13}}$	0.05
$\frac{\partial^{14}}{\partial x^{14}}$	0.05
$\frac{\partial^{15}}{\partial x^{15}}$	0.05
$\frac{\partial^{16}}{\partial x^{16}}$	0.05
$\frac{\partial^{17}}{\partial x^{17}}$	0.05
$\frac{\partial^{18}}{\partial x^{18}}$	0.05
$\frac{\partial^{19}}{\partial x^{19}}$	0.05
$\frac{\partial^{20}}{\partial x^{20}}$	0.05
$\frac{\partial^{21}}{\partial x^{21}}$	0.05
$\frac{\partial^{22}}{\partial x^{22}}$	0.05
$\frac{\partial^{23}}{\partial x^{23}}$	0.05
$\frac{\partial^{24}}{\partial x^{24}}$	0.05
$\frac{\partial^{25}}{\partial x^{25}}$	0.05
$\frac{\partial^{26}}{\partial x^{26}}$	0.05
$\frac{\partial^{27}}{\partial x^{27}}$	0.05
$\frac{\partial^{28}}{\partial x^{28}}$	0.05
$\frac{\partial^{29}}{\partial x^{29}}$	0.05
$\frac{\partial^{30}}{\partial x^{30}}$	0.05
$\frac{\partial^{31}}{\partial x^{31}}$	0.05
$\frac{\partial^{32}}{\partial x^{32}}$	0.05
$\frac{\partial^{33}}{\partial x^{33}}$	0.05
$\frac{\partial^{34}}{\partial x^{34}}$	0.05
$\frac{\partial^{35}}{\partial x^{35}}$	0.05
$\frac{\partial^{36}}{\partial x^{36}}$	0.05
$\frac{\partial^{37}}{\partial x^{37}}$	0.05
$\frac{\partial^{38}}{\partial x^{38}}$	0.05
$\frac{\partial^{39}}{\partial x^{39}}$	0.05
$\frac{\partial^{40}}{\partial x^{40}}$	0.05
$\frac{\partial^{41}}{\partial x^{41}}$	0.05
$\frac{\partial^{42}}{\partial x^{42}}$	0.05
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$\frac{\partial^{45}}{\partial x^{45}}$	0.05
$\frac{\partial^{46}}{\partial x^{46}}$	0.05
$\frac{\partial^{47}}{\partial x^{47}}$	0.05
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$\frac{\partial^{58}}{\partial x^{58}}$	0.05
$\frac{\partial^{59}}{\partial x^{59}}$	0.05
$\frac{\partial^{60}}{\partial x^{60}}$	0.05
$\frac{\partial^{61}}{\partial x^{61}}$	0.05
$\frac{\partial^{62}}{\partial x^{62}}$	0.05
$\frac{\partial^{63}}{\partial x^{63}}$	0.05
$\frac{\partial^{64}}{\partial x^{64}}$	0.05
$\frac{\partial^{65}}{\partial x^{65}}$	0.05
$\frac{\partial^{66$	

## 5

BUR980145US2

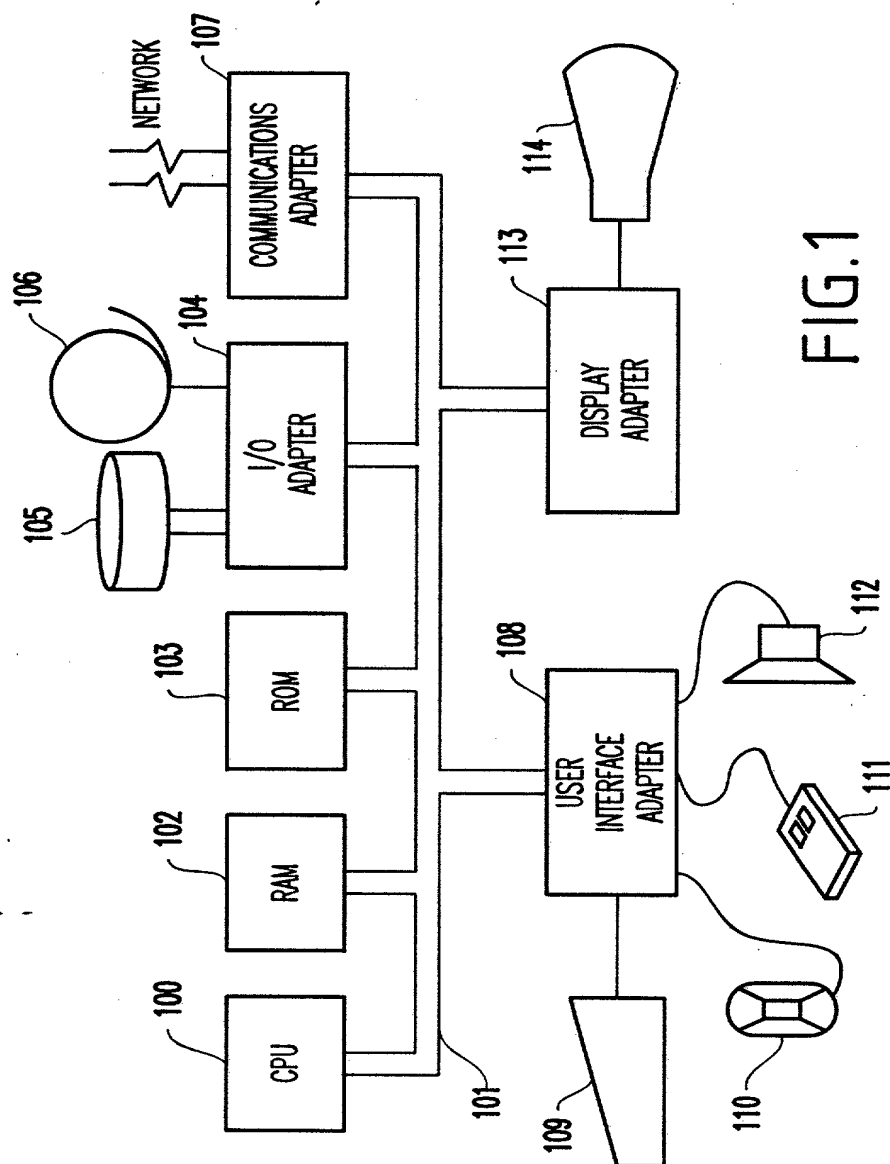


FIG. 1

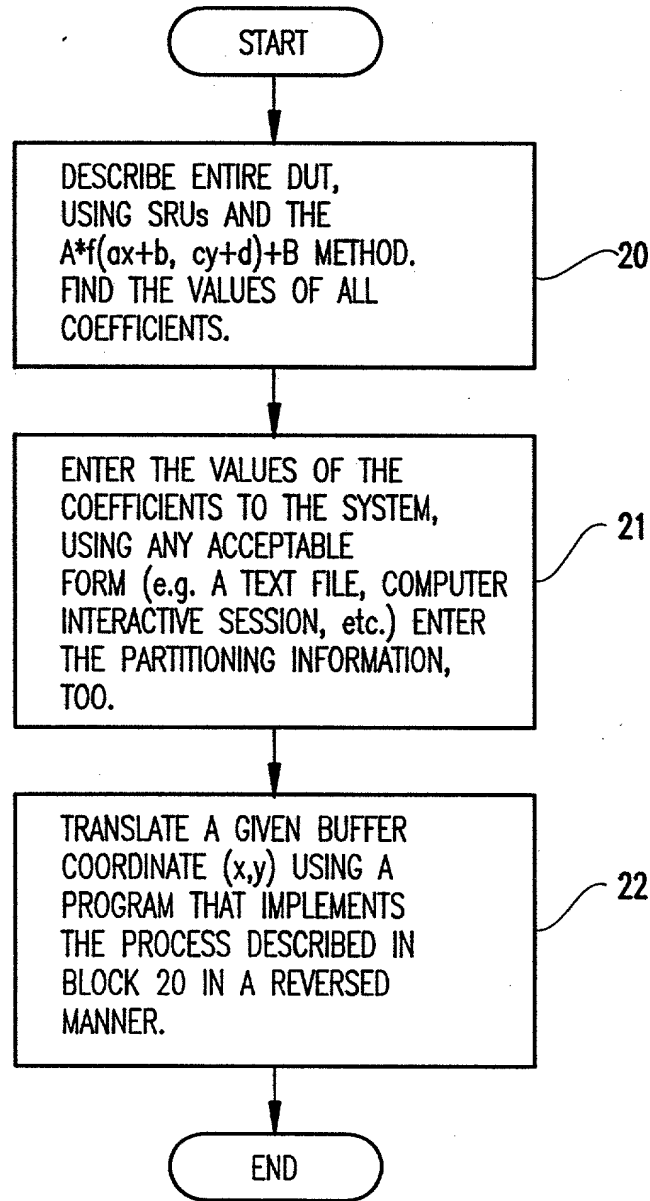


FIG.2

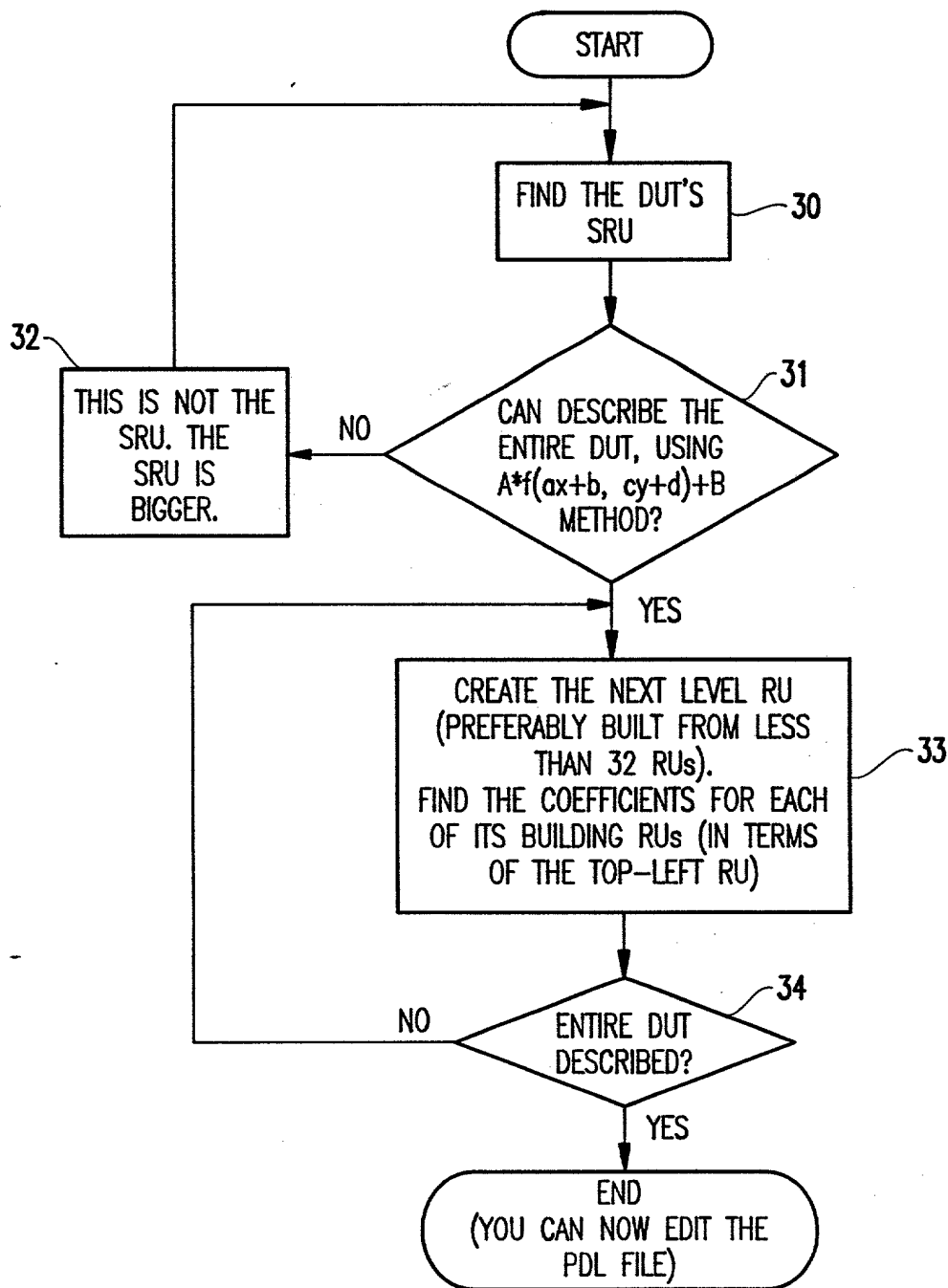


FIG.3

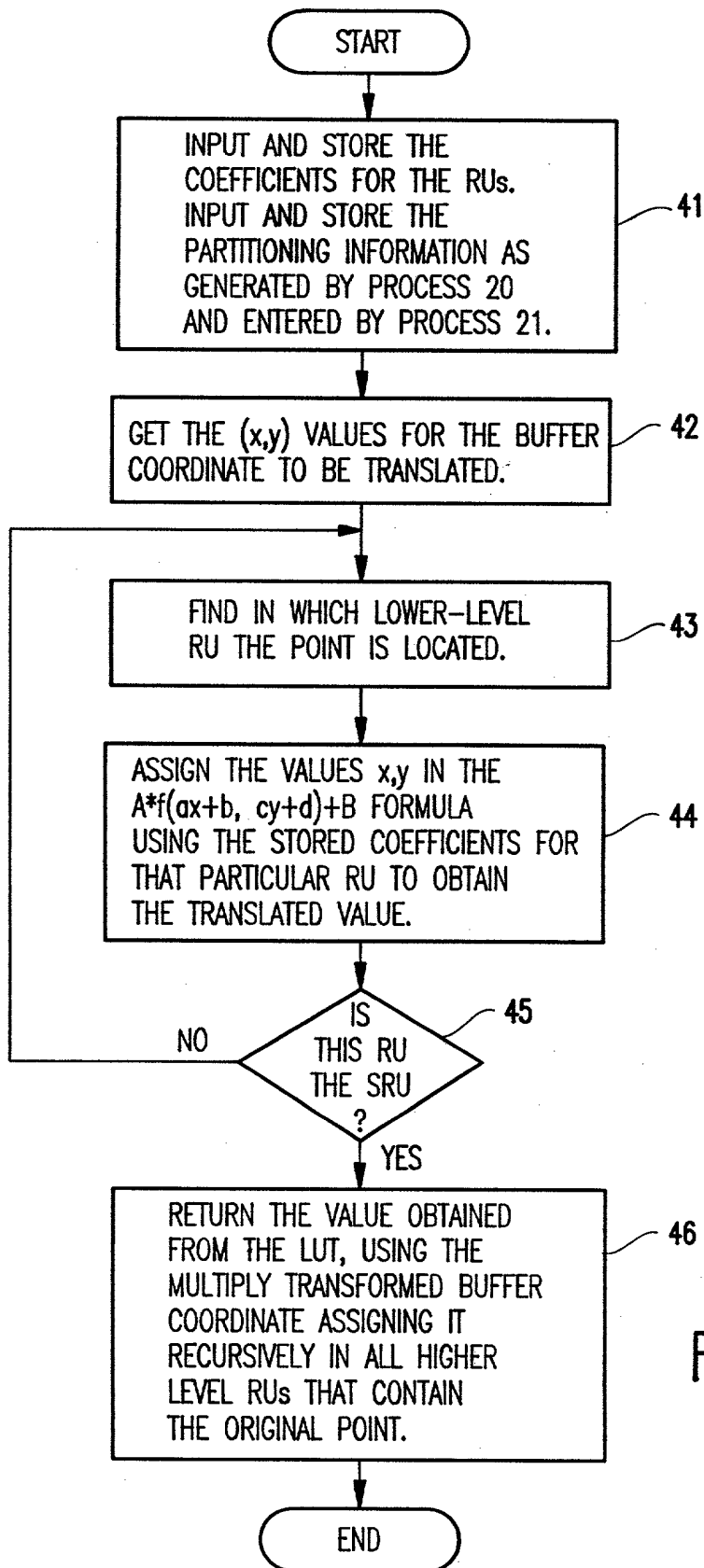


FIG.4

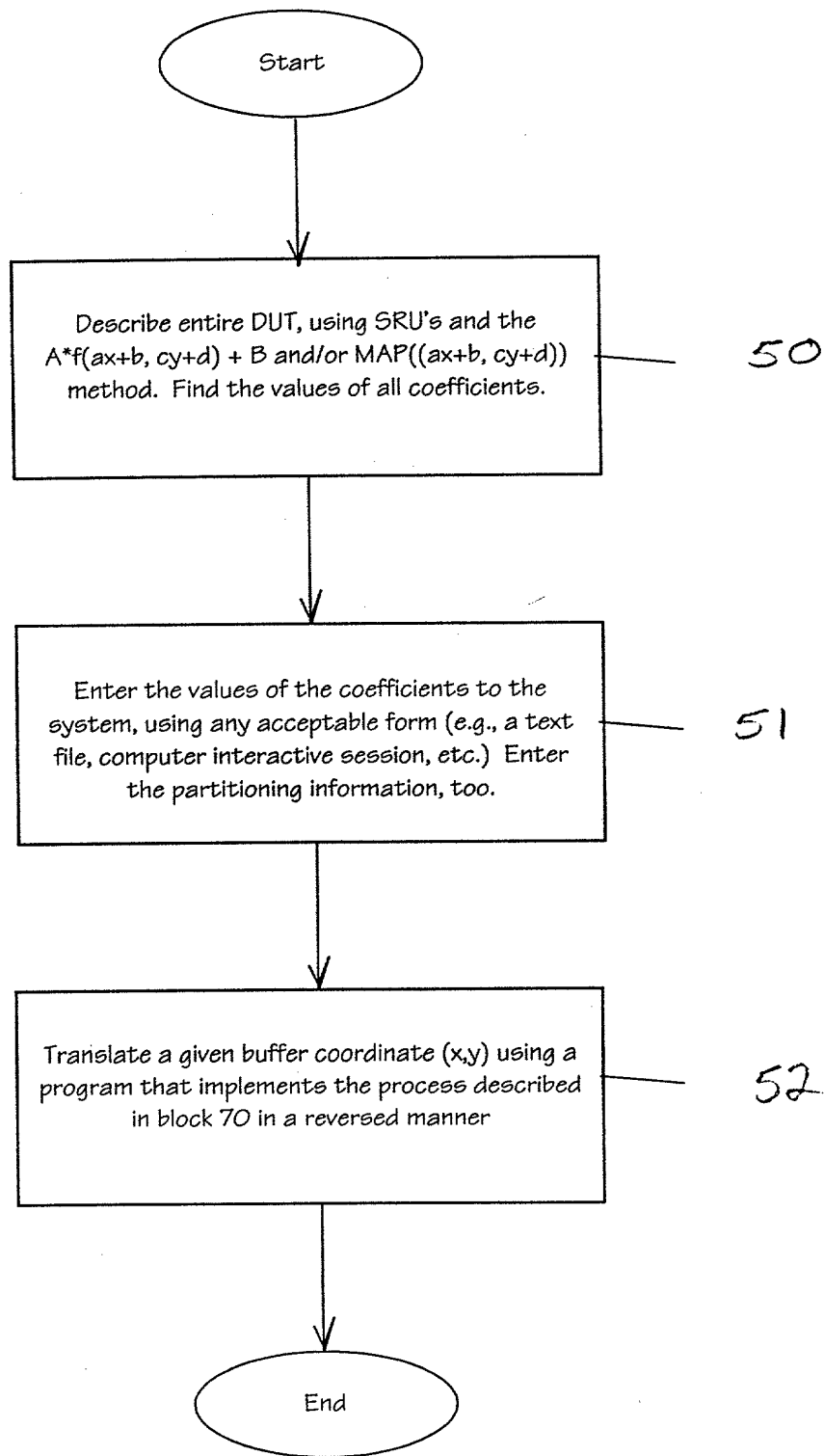


Fig. 5

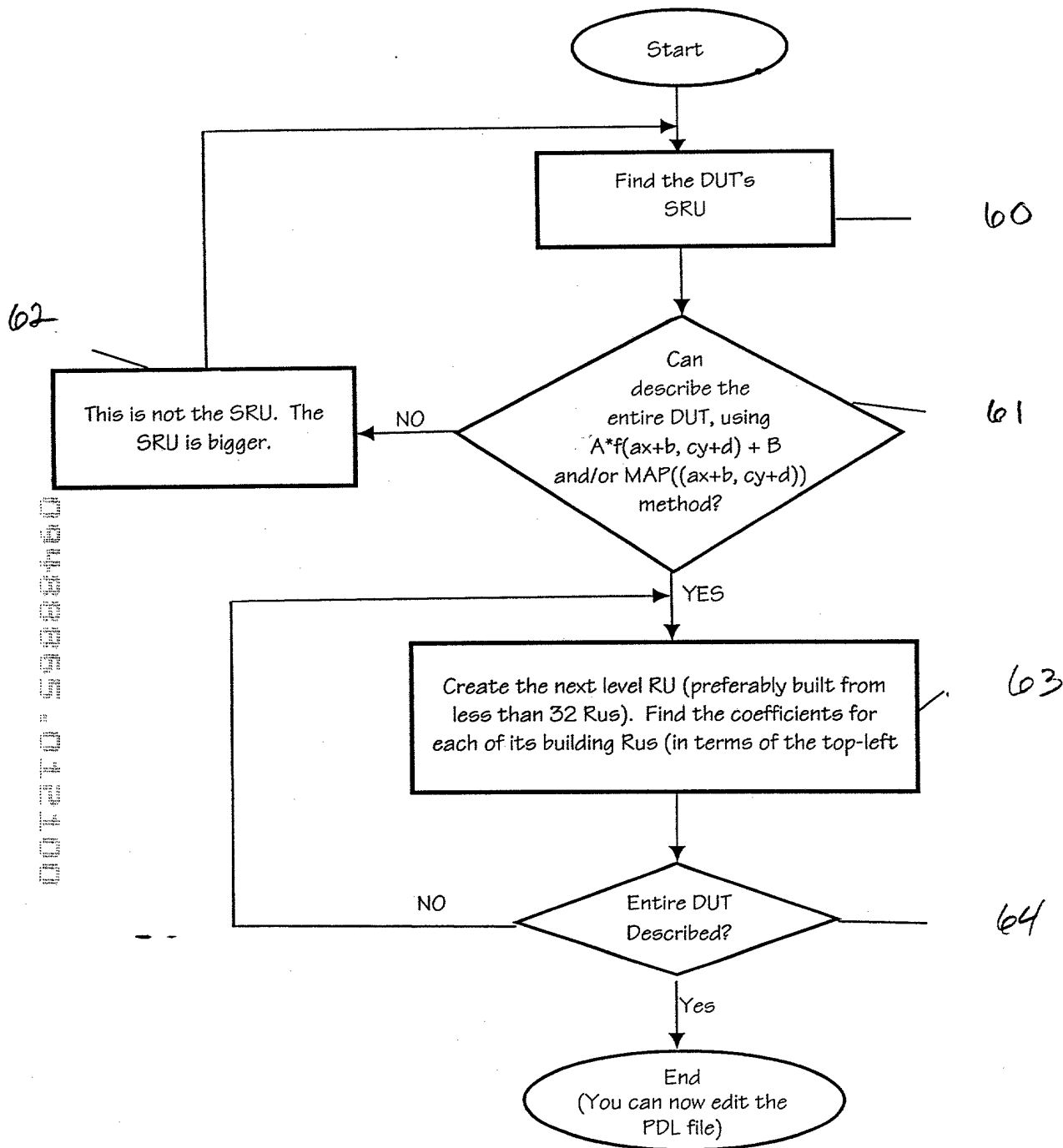


FIG. 6

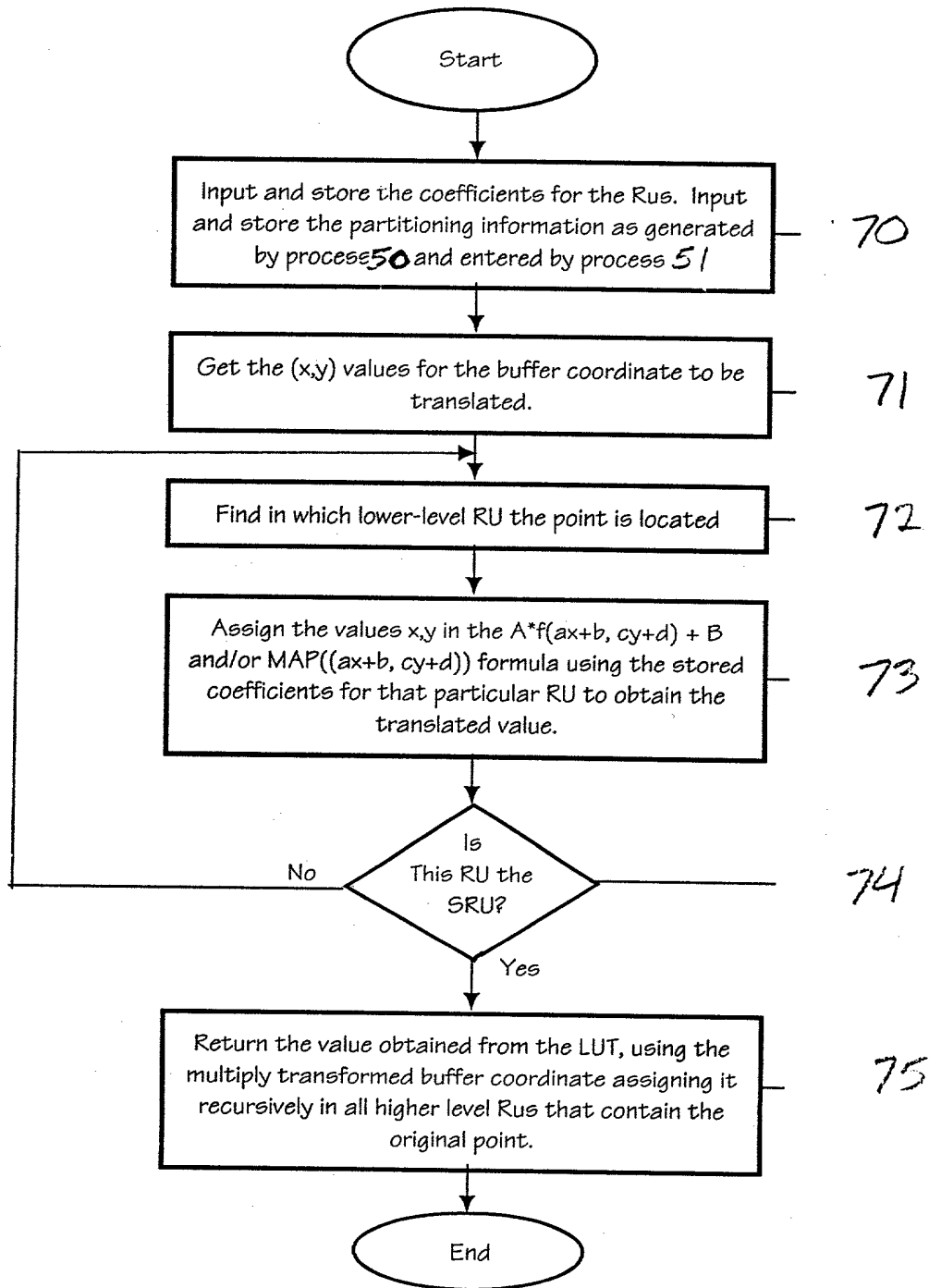


Fig. 7



**DECLARATION AND POWER OF ATTORNEY**

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name;

I believe I am the original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural names are listed below) of the subject matter which is claimed and for which a patent is sought on the invention entitled:

METHOD FOR TRANSLATING TWO-DIMENSIONAL CELL-COORDINATES OF A MEMORY PRODUCT TO N-DIMENSIONAL PHYSICAL ADDRESSES

the specification of which:  
(check one)

☒ (is attached hereto)  
\_\_\_\_\_ was filed on \_\_\_\_\_,  
as Application Serial No. \_\_\_\_\_  
and was amended on \_\_\_\_\_ (if applicable)

I hereby state that I have reviewed and understand the contents of the above identified specification, including the claims, as amended by any amendment referred to above.

I acknowledge the duty to disclose information which is material to the examination of this application in accordance with Title 37, Code of Federal Regulations, § 1.56\*

I hereby claim foreign priority benefits under Title 35, United States Code, § 119 of any foreign application(s) for patent or inventor's certificate listed below and have also identified below any foreign application for patent or inventor's certificate having a filing date before that of the application on which priority is claimed:

Prior Foreign Application(s)			priority claimed	
_____ (Number)	_____ (Country)	_____ (Day/Month/Year Filed)	yes	no
_____ (Number)	_____ (Country)	_____ (Day/Month/Year Filed)	yes	no
_____ (Number)	_____ (Country)	_____ (Day/Month/Year Filed)	yes	no

I hereby claim the benefit under Title 35, United States Code, § 120 of any United States application(s) listed below and, insofar as the subject matter of each of the claims of this application is not disclosed in the prior United States application in the manner provided by the first paragraph of Title 35, United States Code, § 112, I acknowledge the duty to disclose material information as defined in Title 37, Code of Federal Regulations, § 1.56 which occurred between the filing date of the prior application and the national or PCT international filing date of this application:

_____ 09/182,168 (Application Serial No.)	_____ October 29, 1998 (Filing Date)	_____ Pending (Status: patented, pending, abandoned)
---	--	--

**Power of Attorney:** As a named inventor, I hereby appoint Sean M. McGinn, Reg. No. 34, 386, and Frederick W. Gibb, III, Reg. No. 37,629, as attorneys and/or agents to prosecute this application and transact all business in the Patent and Trademark Office connected therewith. All correspondence should be directed to **McGinn & Gibb, P.C., 1701 Clarendon Boulevard, Suite 100, Arlington, Virginia 22209**. Telephone calls should be directed to McGinn & Gibb, P.C. at (703) 294-6699.

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Full Name of Sole

or First Inventor Daniel Ben-EzriInventor's Signature Daniel Ben-Ezri Date January 21, 2000Residence M14 Stonehedge Drive, South Burlington, VT 05403Citizenship IsraelPost Office Address Same as residence

Full Name of Second

Joint Inventor, If Any \_\_\_\_\_

Inventor's Signature \_\_\_\_\_ Date \_\_\_\_\_

Residence \_\_\_\_\_

Citizenship \_\_\_\_\_

Post Office Address \_\_\_\_\_

Full Name of Third

Joint Inventor, If Any \_\_\_\_\_ Date \_\_\_\_\_

Residence \_\_\_\_\_

Citizenship \_\_\_\_\_

Post Office Address \_\_\_\_\_

Full Name of Fourth

Joint Inventor, If Any \_\_\_\_\_ Date \_\_\_\_\_

Residence \_\_\_\_\_

Citizenship \_\_\_\_\_

Post Office Address \_\_\_\_\_

(An additional sheet(s) is/are attached hereto if the present invention includes more than four inventors.)

\*Title 37, Code of Federal Regulations, § 1.56:

(a) A patent by its very nature is affected with a public interest. The public interest is best served, and the most effective patent examination occurs when, at the time an application is being examined, the Office is aware of and evaluates the teachings of all information material to patentability. Each individual associated with the filing and prosecution of a patent application has a duty of candor and good faith toward the Patent and Trademark Office, which includes a duty to disclose to the Office all information known to that individual to be material to patentability as defined in this section. The duty to disclose information exists with respect to each pending claim until the claim is canceled or withdrawn from consideration, or the application becomes abandoned.

(b) Under this section, information is material to patentability when it is not cumulative to information already of record or being made of record in the application, and (1) it establishes by itself or in combination with other information, a prima facie case of unpatentability; or (2) it refutes, or is inconsistent with, a position the applicant takes in: (i) opposing an argument of unpatentability relied on by the Office, or (ii) asserting an argument of patentability.